DATA SHEET

SILICON POWER MOS FET

NE5520379A

3.2 V OPERATION SILICON RF POWER LDMOS FET FOR GSM/DCS DUAL-BAND PHONE TRANSMISSION AMPLIFIERS

DESCRIPTION

The NE5520379A is an N-channel silicon power MOS FET specially designed as the transmission power amplifier for 3.2 V GSM 900 handsets. Dies are manufactured using our NEWMOS technology and housed in a surface mount package. This device can deliver 34.6 dBm output power with 68% power efficiency at 915 MHz under the 2.8 V supply voltage.

FEATURES

- High output power : P_{out} = 35.5 dBm TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 915 MHz, P_{in} = 25 dBm)
  : P_{out} = 33.0 dBm TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 1 785 MHz, P_{in} = 25 dBm)
- High power added efficiency : η_{add} = 65% TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 915 MHz, P_{in} = 25 dBm)
  : η_{add} = 35% TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 1 785 MHz, P_{in} = 25 dBm)
- High linear gain : G_L = 16.0 dB TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 915 MHz, P_{in} = 10 dBm)
  : G_L = 8.5 dB TYP. (V_{DS} = 3.2 V, V_{GS} = 2.5 V, f = 1 785 MHz, P_{in} = 10 dBm)
- Surface mount package : 5.7 × 5.7 × 1.1 mm MAX.
- ★ Single supply : V_{DS} = 2.8 to 6.0 V

APPLICATIONS

- Digital cellular phones : 3.2 V GSM/DCS Dual-Band handsets
- Others : General purpose amplifiers for 1.6 to 2.0 GHz TDMA applications

ORDERING INFORMATION

Part Number	Package	Marking	Supplying Form
NE5520379A-T1	79A	A3	• 12 mm wide embossed taping • Gate pin face the perforation side of the tape • Qty 1 kpcs/reel
NE5520379A-T1A			• 12 mm wide embossed taping • Gate pin face the perforation side of the tape • Qty 5 kpcs/reel

Remark To order evaluation samples, contact your nearby sales office.
Part number for sample order: NE5520379A

Caution Observe precautions when handling because these devices are sensitive to electrostatic discharge.

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Printed in Japan

The mark ★ shows major revised points.

ABSOLUTE MAXIMUM RATINGS (T_A = +25°C)

Parameter	Symbol	Ratings	Unit
★ Drain to Source Voltage	V_{DS}	15.0	V
Gate to Source Voltage	V_{GS}	5.0	V
Drain Current	I_D	1.5	A
Drain Current (Pulse Test)	I_D Note	3.0	A
Total Power Dissipation	P_{tot}	20	W
Channel Temperature	T_{ch}	125	°C
Storage Temperature	T_{stg}	–65 to +125	°C

Note Duty Cycle ≤ 50%, T_{on} ≤ 1 s

RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
★ Drain to Source Voltage	V_{DS}		2.8	3.2	6.0	V
Gate to Source Voltage	V_{GS}		0	2.5	3.5	V
Drain Current (Pulse Test)	I_D	Duty Cycle ≤ 50%, T_{on} ≤ 1 s	–	1.75	2.0	A
Input Power	P_{in}	f = 1.8 GHz, V_{DS} = 3.6 V	24	25	26	dBm

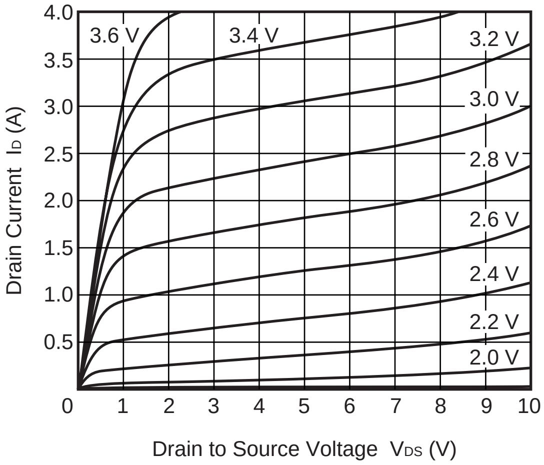
ELECTRICAL CHARACTERISTICS (T_A = +25°C)

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
★ Gate to Source Leak Current	I_{GSS}	V_{GS} = 6.0 V	–	–	100	nA
★ Drain to Source Leakage Current (Zero Gate Voltage Drain Current)	I_{DSS}	V_{DS} = 8.5 V	–	–	100	nA
Gate Threshold Voltage	V_{th}	V_{DS} = 3.5 V, I_D = 1 mA	1.0	1.35	2.0	V
Transconductance	G_m	V_{DS} = 3.5 V, I_D = 0.8 to 1.0 A	–	2.5	–	S
Drain to Source Breakdown Voltage	BV_{DSS}	I_{DSS} = 10 μA	15	20	–	V
Thermal Resistance	R_{th}	Channel to Case	–	–	5	°C/W
Linear Gain	G_L	f = 915 MHz, P_{in} = 10 dBm, V_{DS} = 3.2 V, V_{GS} = 2.5 V, **Note**	–	16.0	–	dB
Output Power	P_{out}	f = 915 MHz, P_{in} = 25 dBm, V_{DS} = 3.2 V, V_{GS} = 2.5 V, **Note**	–	35.5	–	dBm
Drain Efficiency	η_d		–	68	–	%
Power Added Efficiency	η_{add}		–	65	–	%
Linear Gain	G_L	f = 1 785 MHz, P_{in} = 10 dBm, V_{DS} = 3.2 V, V_{GS} = 2.5 V, **Note**	–	8.5	–	dB
Output Power	P_{out}	f = 1 785 MHz, P_{in} = 25 dBm, V_{DS} = 3.2 V, V_{GS} = 2.5 V, **Note**	31.0	33.0	–	dBm
Drain Efficiency	η_d		29	38	–	%
Power Added Efficiency	η_{add}		–	35	–	%

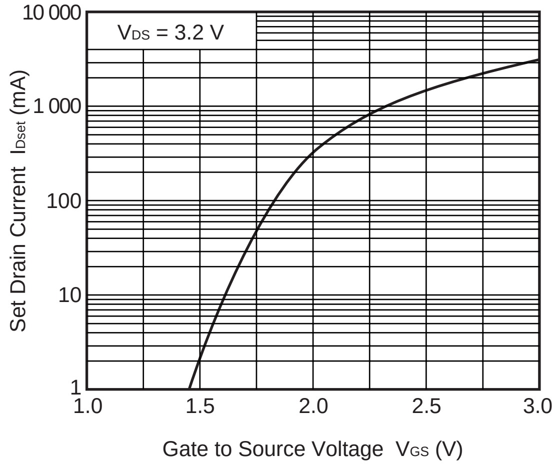
Note DC performance is 100% testing. RF performance is testing several samples per wafer.
Wafer rejection criteria for standard devices is 1 reject for several samples.

★ TYPICAL CHARACTERISTICS (T_A = +25°C)

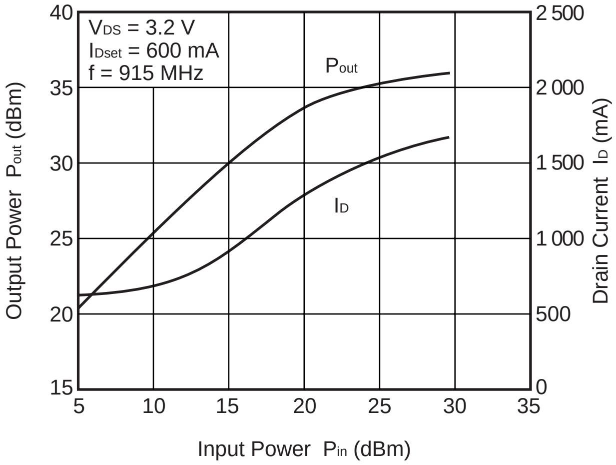
DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE



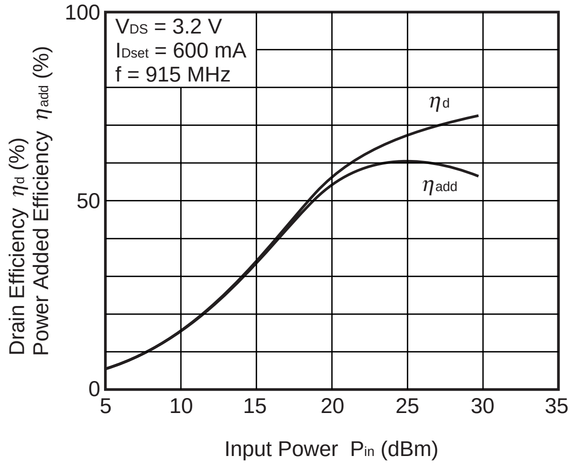
SET DRAIN CURRENT vs.
GATE TO SOURCE VOLTAGE



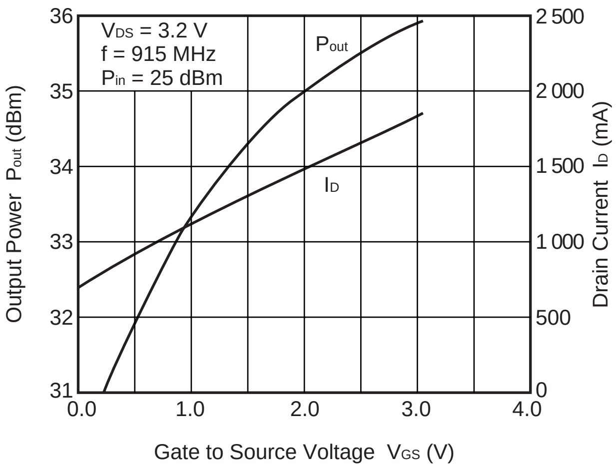
OUTPUT POWER, DRAIN CURRENT
vs. INPUT POWER



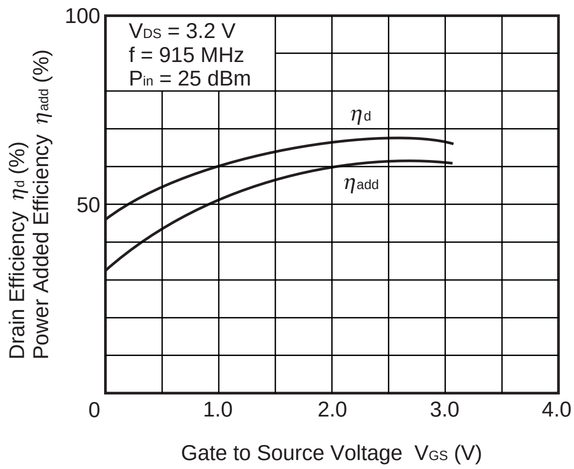
DRAIN EFFICIENCY, POWER ADDED
EFFICIENCY vs. INPUT POWER



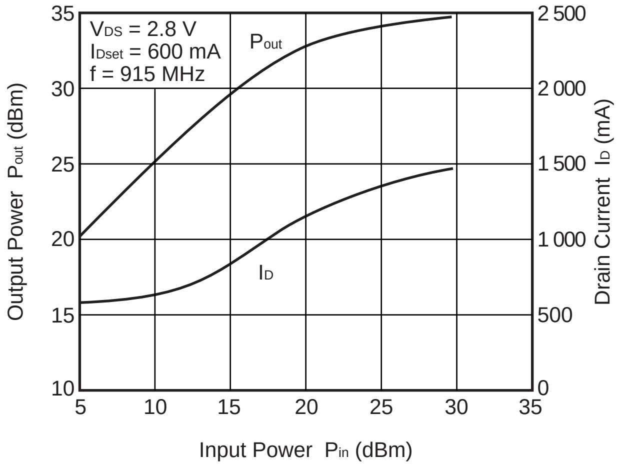
OUTPUT POWER, DRAIN CURRENT
vs. GATE TO SOURCE VOLTAGE



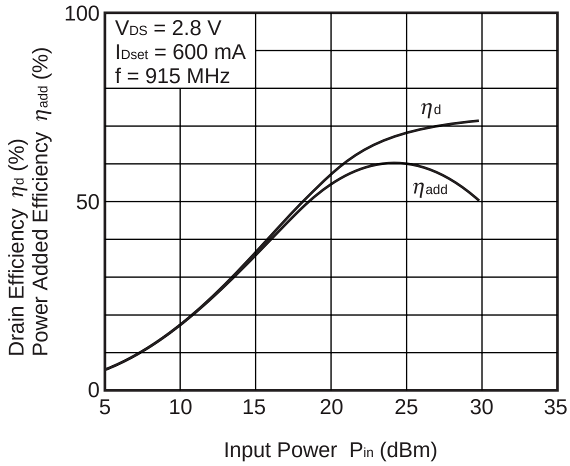
DRAIN EFFICIENCY, POWER ADDED
EFFICIENCY vs. GATE TO SOURCE VOLTAGE



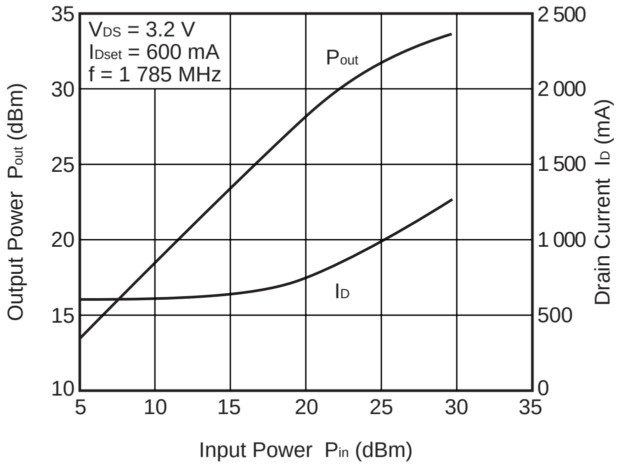
OUTPUT POWER, DRAIN CURRENT vs. INPUT POWER (915 MHz)



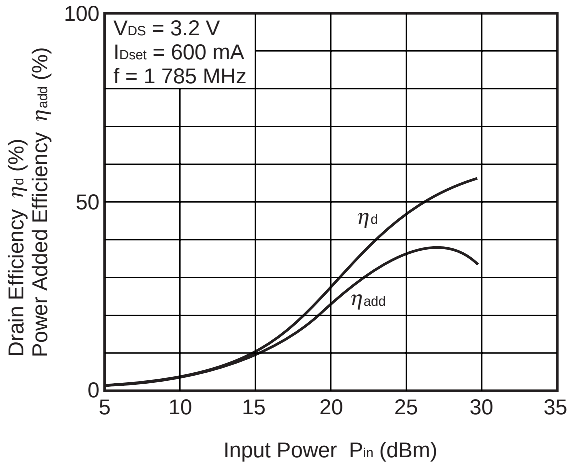
DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. INPUT POWER



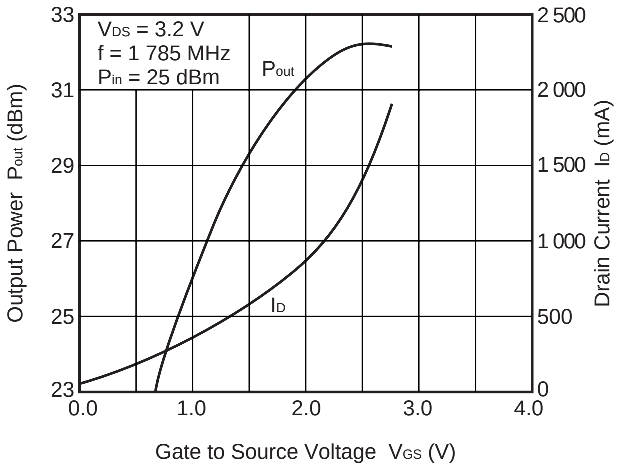
OUTPUT POWER, DRAIN CURRENT vs. INPUT POWER (1 785 MHz)



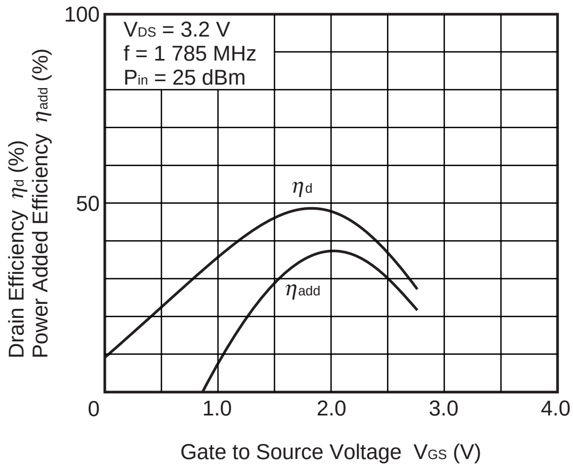
DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. INPUT POWER



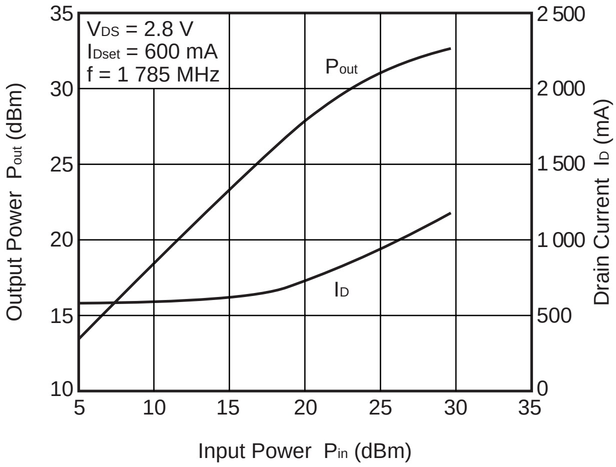
OUTPUT POWER, DRAIN CURRENT vs. GATE TO SOURCE VOLTAGE



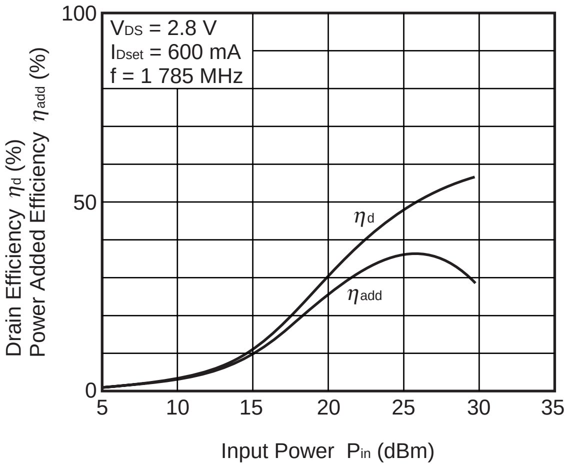
DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. GATE TO SOURCE VOLTAGE



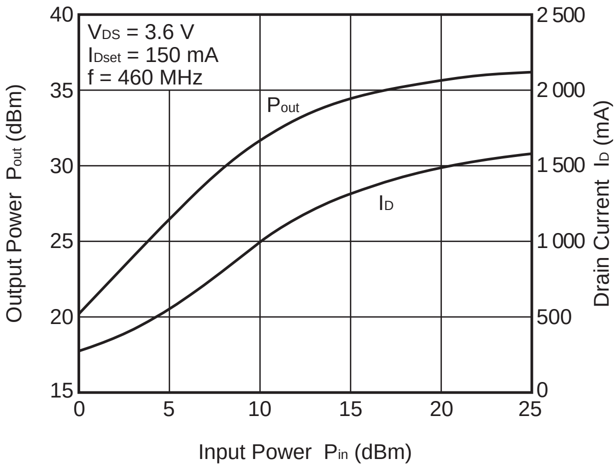
OUTPUT POWER, DRAIN CURRENT vs. INPUT POWER (1 785 MHz)



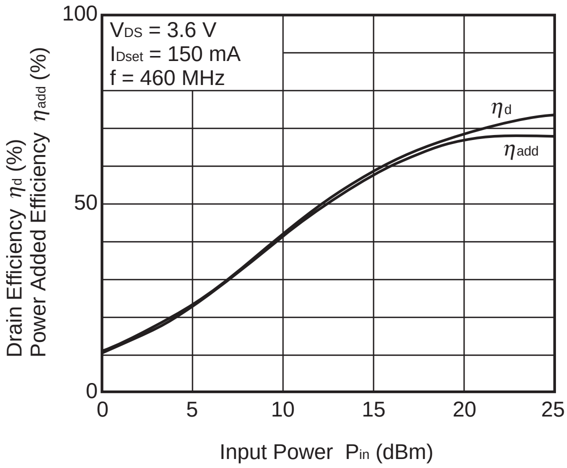
DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. INPUT POWER



OUTPUT POWER, DRAIN CURRENT vs. INPUT POWER (460 MHz)



DRAIN EFFICIENCY, POWER ADDED EFFICIENCY vs. INPUT POWER



Remark The graphs indicate nominal characteristics.

S-PARAMETERS

S-parameters/Noise parameters are provided on the NEC Compound Semiconductor Devices Web site in a form (S2P) that enables direct import to a microwave circuit simulator without keyboard input.

Click here to download S-parameters.

[RF and Microwave] → [Device Parameters]

URL http://www.csd-nec.com/

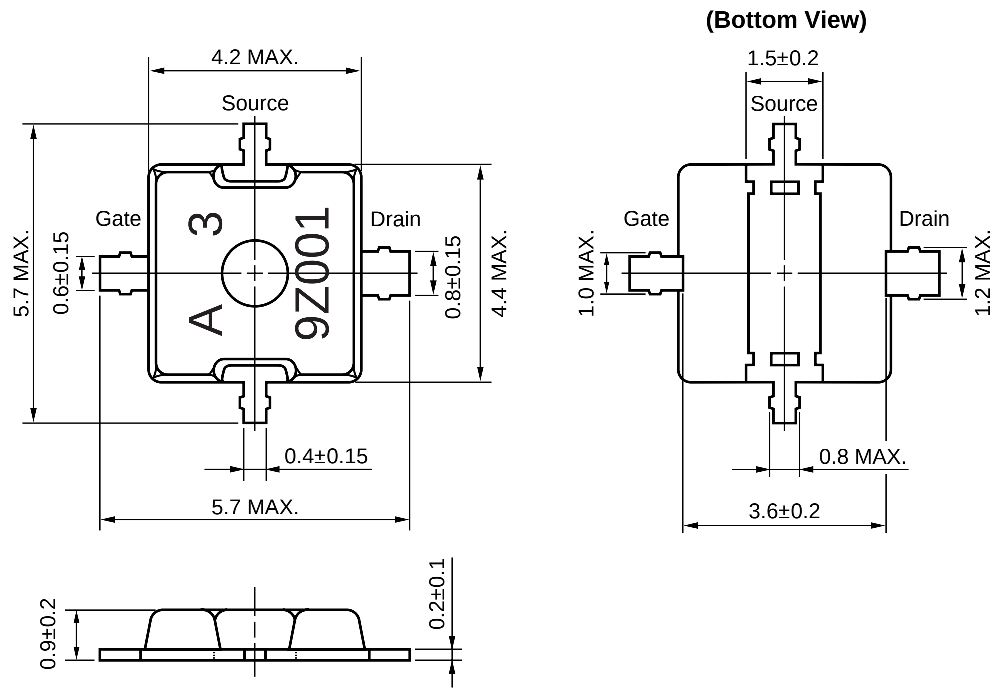
LARGE SIGNAL IMPEDANCE (V_{DS} = 3.2 V, I_{Dset} = 600 mA, P_{in} = 25 dBm)

f (MHz)	Z_{in} (Ω)	Z_{OL} (Ω) Note
1 785	TBD	TBD

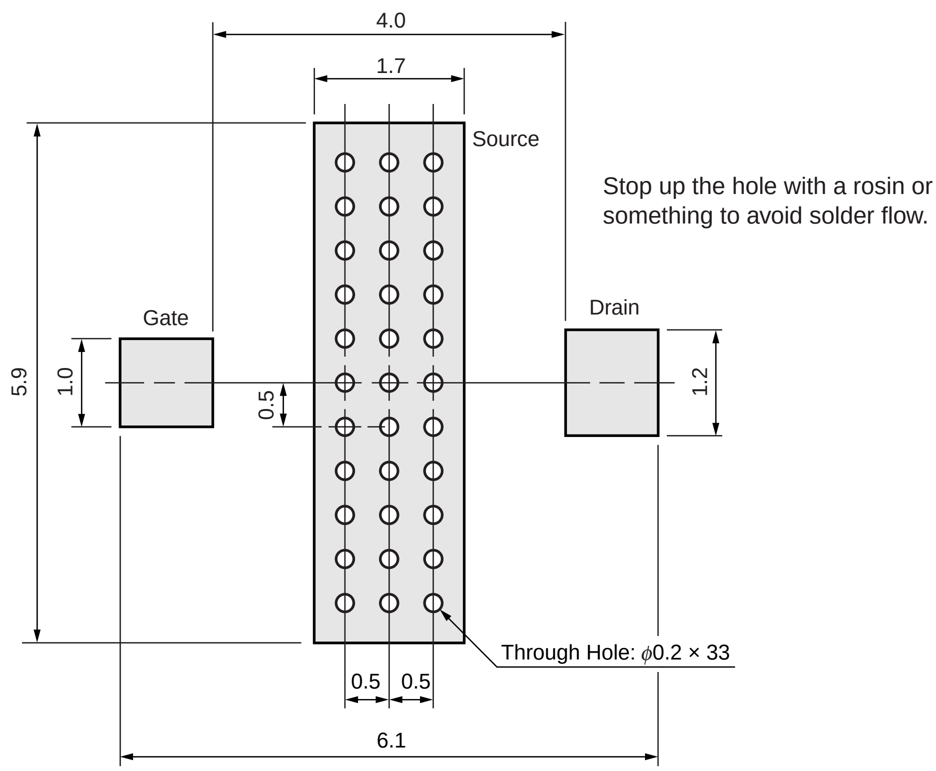
Note Z_{OL} is the conjugate of optimum load impedance at given voltage, idling current, input power and frequency.

★ **PACKAGE DIMENSIONS**

79A (UNIT: mm)



79A PACKAGE RECOMMENDED P.C.B. LAYOUT (UNIT: mm)



RECOMMENDED SOLDERING CONDITIONS

This product should be soldered and mounted under the following recommended conditions. For soldering methods and conditions other than those recommended below, contact your nearby sales office.

Soldering Method	Soldering Conditions		Condition Symbol
Infrared Reflow	Peak temperature (package surface temperature) Time at peak temperature Time at temperature of 220°C or higher Preheating time at 120 to 180°C Maximum number of reflow processes Maximum chlorine content of rosin flux (% mass)	: 260°C or below : 10 seconds or less : 60 seconds or less : 120±30 seconds : 3 times : 0.2%(Wt.) or below	IR260
VPS	Peak temperature (package surface temperature) Time at temperature of 200°C or higher Preheating time at 120 to 150°C Maximum number of reflow processes Maximum chlorine content of rosin flux (% mass)	: 215°C or below : 25 to 40 seconds : 30 to 60 seconds : 3 times : 0.2%(Wt.) or below	VP215
Wave Soldering	Peak temperature (molten solder temperature) Time at peak temperature Preheating temperature (package surface temperature) Maximum number of flow processes Maximum chlorine content of rosin flux (% mass)	: 260°C or below : 10 seconds or less : 120°C or below : 1 time : 0.2%(Wt.) or below	WS260
Partial Heating	Peak temperature (pin temperature) Soldering time (per pin of device) Maximum chlorine content of rosin flux (% mass)	: 350°C or below : 3 seconds or less : 0.2%(Wt.) or below	HS350-P3

Caution Do not use different soldering methods together (except for partial heating).

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